## Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination
10580401	CHEN ET AL.
Examiner	Art Unit
Awet Haile	2474

## **SEARCHED**

Class	Subclass	Date	Examiner
370	395.2, 395.5, 252	10/31/2009	MA
370	231, 232, 233, 235, 236.1, 395.5, 468	5/7/2010	A.H
Above	Updated	9/30/2010	A.H
Above	Updated	2/2/2011	A.H
Above	Updated	7/16/2011	A.H
Above	Updated	11/21/2011	A.H

## **SEARCH NOTES**

Search Notes	Date	Examiner
East Search (updated)	2/17/2009	MA
Inventor's/Asignee's Search	10/31/2009	MA
NPL(IEEE, Books and so)	10/31/2009	MA
PLUS Search	10/31/2009	MA
Google/patents/scholar	10/31/2009	Ma
East text search	5/7/2010	A.H
East class/subclass limited search 370/395.5, 370/236.1	5/7/2010	A.H
Inventor's search	5/7/2010	A.H
East class/subclass limited search 370/395.5, 370/236.1	9/30/2010	A.H
Inventor's search	9/30/2010	A.H
East text search	9/30/2010	A.H
East class/subclass limited search 370/395.5, 370/236.1	2/2/2011	A.H
Inventor's search	2/2/2011	A.H
Inventor search(Palm and East)	7/16/2011	A.H
East limited text search with the above class/subclass	7/16/2011	A.H
East text and class/subclass	7/16/2011	A.H
Inventor search(Palm and East)	11/21/2011	A.H
East text and class/subclass	11/21/2011	A.H
East limited text search with the above class/subclass	11/21/2011	A.H
Consult with Aung Moe(SPE)	11/16/2011	A.H

## INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
370	331, 468	11/21/2011	A.H

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
	text search with the above class/subclass(see attaced interference search report)	11/21/2011	A.H

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